

Notice of References Cited	Application/Control No. 10/533,712		Applicant(s)/Patent Under Reexamination LOW, YEE CHEOK	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,646,278 A	02-1987	Okano, Takashi	369/30.12
*	B	US-5,847,719 A	12-1998	Yamaguchi et al.	346/134
*	C	US-6,175,538 B1	01-2001	Ogata, Hitoshi	369/30.16
*	D	US-6,320,824 B1	11-2001	Hirata, Minoru	369/53.29
*	E	US-2003/0072237 A1	04-2003	Hashimoto et al.	369/53.28
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	X				

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